

MOSFET

StrongIRFET™2 Power-Transistor, 40 V

Features

- Optimized for wide range of applications
- N-channel, normal level
- 100% avalanche tested
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

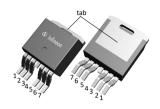
Product validation

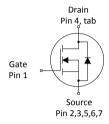
Qualified according to JEDEC Standard

Table 1 Key Performance Parameters

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Parameter	Value	Unit				
V _{DS}	40	V				
$R_{\mathrm{DS(on),max}}$	1.35	mΩ				
I _D	239	A				
Q _{oss}	117	nC				
Q _G (0V10V)	106	nC				











Type/Ordering Code	Package	Marking	Related Links
IPF013N04NF2S	PG-TO263-7	013N04NS	-

Public

StrongIRFET™2 Power-Transistor, 40 V IPF013N04NF2S



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1 Maximum ratings

at T_{Δ} =25 °C, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Мах.	Ullit	Note/ Test Condition	
Continuous drain current ¹⁾	I _D	-	-	239 184 40		$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25°C, $R_{\rm THJA}$ =40°C/W ²⁾	
Pulsed drain current ³⁾	I _{D,pulse}	-	-	956	А	T _A =25 °C	
Avalanche energy, single pulse ⁴⁾	E _{AS}	-	-	283	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 Ω	
Gate source voltage	V_{GS}	-20	-	20	V	-	
Power dissipation	P_{tot}	-	-	231 3.8	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =40 °C/W ²⁾	
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$	-55	-	175	°C	-	

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See Diagram 3 for more detailed information

⁴⁾ See Diagram 13 for more detailed information



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			l lmit	Nieto/Test Condition
raiametei	Syllibot	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Thermal resistance, junction - case	R_{thJC}	-	-	0.65	°C/W	-
Thermal resistance, junction - ambient, 6 cm ² cooling area ⁵⁾	R_{thJA}	-	-	40	°C/W	-
Thermal resistance, junction - ambient, minimal footprint	R_{thJA}	-	-	62	°C/W	-

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



3 Electrical characteristics

at T_i =25 °C, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition	
raiailletei	Syllibot	Min.	Тур.	Мах.	Ollic	Note/ Test Condition	
Drain-source breakdown voltage	$V_{(BR)DSS}$	40	-	-	V	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA	
Gate threshold voltage	$V_{\rm GS(th)}$	2.1	2.8	3.4	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 126 \mu{\rm A}$	
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	$V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C $V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C	
Gate-source leakage current	I_{GSS}	-	10	100	nA	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V	
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	1.08 1.24		mΩ	V_{GS} =10 V, I_{D} =100 A V_{GS} =6 V, I_{D} =50 A	
Gate resistance	R_{G}	-	2.0	-	Ω	-	
Transconductance ⁶⁾	g_{fs}	195	-	-	S	$ V_{\rm DS} \ge 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D} = 100 \text{ A}$	

⁶⁾ Defined by design. Not subject to production test.

Table 5 Dynamic characteristics

Darameter	Symbol	Values			Unit	Note / Test Condition	
Parameter	Syllibol	Min.	Тур.	Мах.		Note/ Test Condition	
Input capacitance	C _{iss}	-	7500	-	pF	V _{GS} =0 V, V _{DS} =20 V, <i>f</i> =1 MHz	
Output capacitance	Coss	-	2760	-	pF	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =20 V, f =1 MHz	
Reverse transfer capacitance	C _{rss}	-	145	-	pF	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =20 V, f =1 MHz	
Turn-on delay time	$t_{d(on)}$	-	20	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω	
Rise time	t _r	-	42	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω	
Turn-off delay time	$t_{ m d(off)}$	-	47	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω	
Fall time	t_{f}	-	20	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 Ω	

Table 6 Gate charge characteristics 7)

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailietei	Syllibot	Min.	Тур.	Мах.	Onic	Note/ Test Condition
Gate to source charge	$Q_{ m gs}$	-	32	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	21	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate to drain charge	$Q_{ m gd}$	-	20	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Switching charge	Q_{sw}	-	31	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total ⁸⁾	Q_{g}	_	106	159	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V



Table 6 Gate charge characteristics 7)

Parameter	Symbol	Values			Unit	Note/ Test Condition	
raiametei	Syllibol	Min.	Тур.	Мах.	Offic	Note/ Test Condition	
Gate plateau voltage	$V_{ m plateau}$	-	4.3	-	V	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge total, sync. FET	$Q_{\mathrm{g(sync)}}$	-	94	-	nC	$V_{\rm DS}$ =0.1 V, $V_{\rm GS}$ =0 to 10 V	
Output charge	$Q_{\rm oss}$	-	117	-	nC	V _{DS} =20 V, V _{GS} =0 V	

 $^{^{7)}\ \ \, \}text{See}$ "Gate charge waveforms" for parameter definition

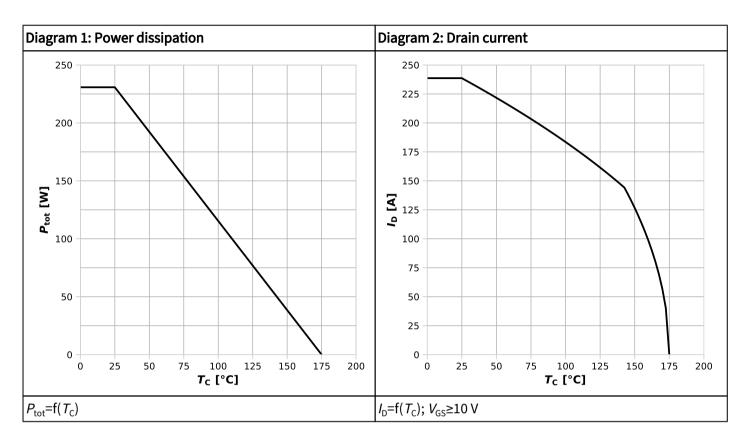
Table 7 Reverse diode

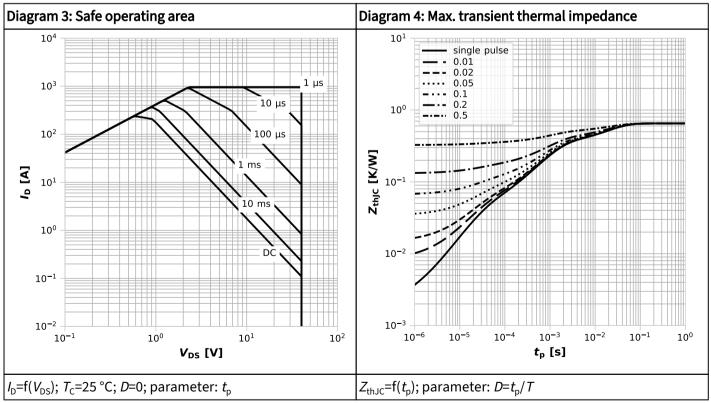
Parameter	Symbol	Values			Unit	Note/Test Condition	
raiailietei	Syllibol	Min.	Тур.	Max.	Offic	Note/ Test Condition	
Diode continuous forward current	I_{S}	-	-	181	А	<i>T</i> _C =25 °C	
Diode pulse current	I _{S,pulse}	-	-	956	А	<i>T</i> _C =25 °C	
Diode forward voltage	$V_{\rm SD}$	-	0.85	1	V	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =100 A, $T_{\rm j}$ =25 °C	
Reverse recovery time	t_{rr}	-	49	-	ns	V_R =20 V, I_F =100 A, di_F/dt =100 A/ μ s	
Reverse recovery charge	$Q_{\rm rr}$	-	53	-	nC	V_{R} =20 V, I_{F} =100 A, di_{F}/dt =100 A/ μ s	
Reverse recovery time	t _{rr}	-	36	-	ns	$V_{\rm R}$ =20 V, $I_{\rm F}$ =100 A, d $i_{\rm F}$ /d t =500 A/ μ s	
Reverse recovery charge	$Q_{\rm rr}$	-	168	-	nC	$V_{\rm R}$ =20 V, $I_{\rm F}$ =100 A, d $i_{\rm F}$ /d t =500 A/ μ s	

⁸⁾ Defined by design. Not subject to production test.

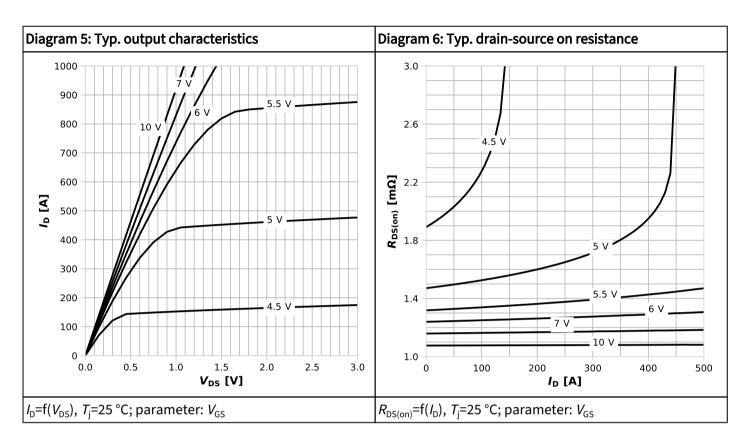


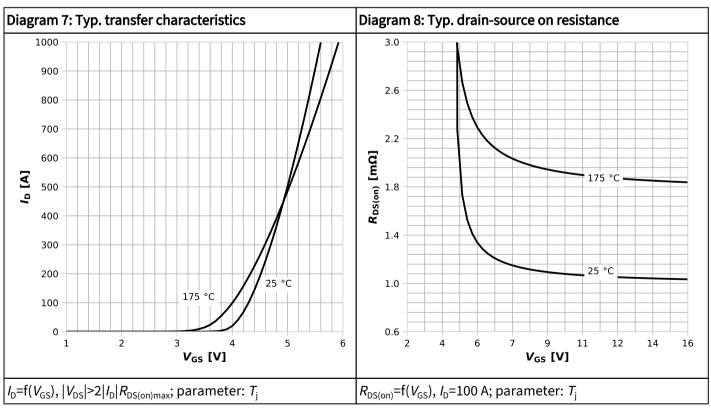
4 Electrical characteristics diagrams



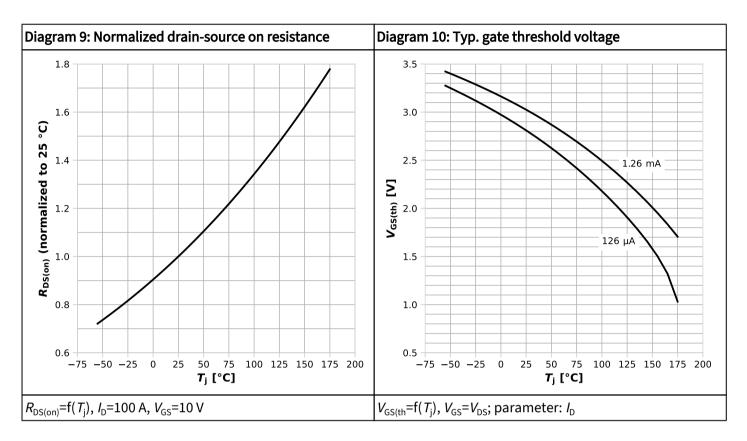


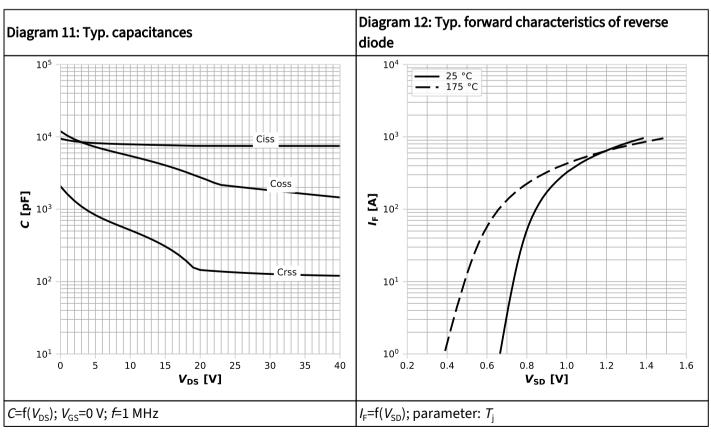




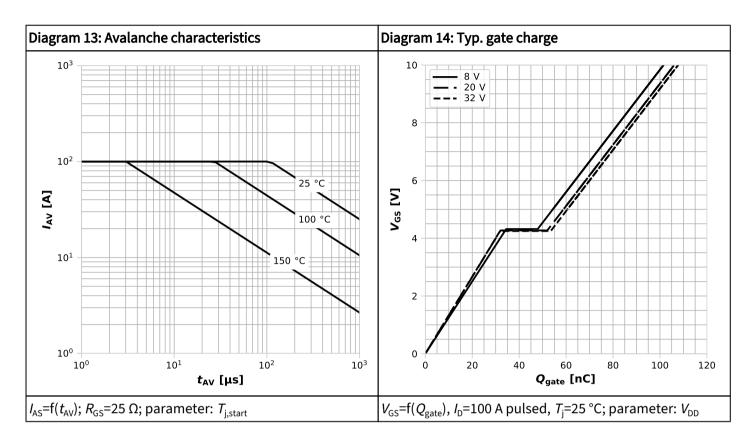


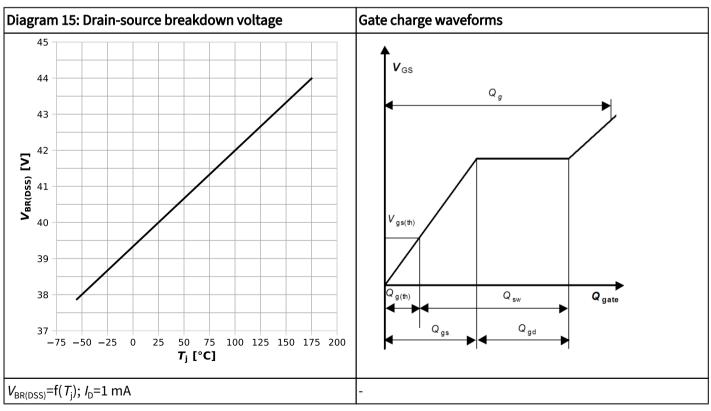






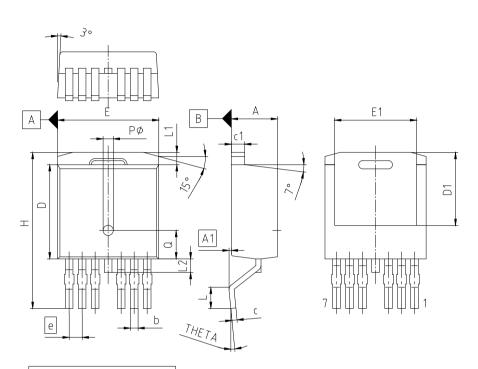








5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TO26	3-7-U02				
DIMENSIONS	MILLIM	IETERS				
DIMENSIONS	MIN.	MAX.				
Α	4.30	4.70				
A1	0.00	0.25				
b	0.65	0.85				
С	0.45	0.60				
c1	1.25	1.40				
D	9.00	9.40				
D1	6.86	7.42				
E	9.68	10.08				
E1	7.70	8.30				
е	1.27					
N	7					
Н	14.61	15.88				
L	1.78	2.79				
L1	0.00	1.60				
L2	0.00	1.78				
THETA	0°	- 8°				
PØ	0.90	1.10				
Q	2.	78				

Figure 1 Outline PG-TO263-7, dimensions in mm



Revision History

IPF013N04NF2S

Revision 2024-10-14, Rev. 2.1

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2022-10-11	Release of final version
2.1	2024-10-14	Added trr and Qrr at diF/dt=100 A/μs

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